 Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	•
09/633,782	LEE ET AL.	
Examiner	Art Unit	
HOAN C. NGUYEN	2871	

	SEAR	CHED	
Class	Subclass	Date	Examiner
349	42-44	4/2/2007	СНИ
349	110	4/2/2007	СНИ
345	92	4/2/2007	CHN
257	59 & 72	4/2/2007	СНИ

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
all subclias and text		4/2/2007	CHN

SEARCH NOT (INCLUDING SEARCH)
_	DATE	EXMR
East search in US-PGPUB, USPAT, EPO, JPO, Derwent and IBM_TDB	4/2/2007	СНИ
·		
· · · · · · · · · · · · · · · · · · ·		